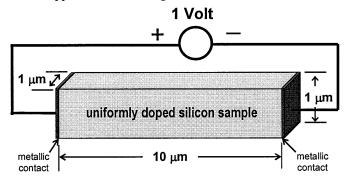
acceptor atom

Problem 1 [15 points]: Semiconductor Basics

Consider a Si sample of length 10 μ m and cross-sectional area 1μ m², uniformly doped with 10^{16} cm⁻³ boron, maintained at T = 300K. 1 Volt is applied across its length, as shown below:



a) Estimate the resistance of this sample. [6 pts]

Since NA > ND, this sample is
$$p-type$$
: $P = N_A - N_D = 10^{16} \text{cm}^{-3}$

$$N = \frac{n_i^2}{p} = \frac{10^{20}}{10^{16}} = \frac{10^4 \text{cm}^{-3}}{10^{16}}$$

From plot on Page 1, up =450 cm2/V.s and un = 1200 cm2/V.s

$$R = R = 1.4 \frac{10 \times 10^{-4}}{(10^{-4})^2} = 1.4 \times 10^5 \Omega = 140 \text{ kg}$$

b) Estimate the electron drift velocity. [5 pts]

$$\mathcal{E} = \frac{1V}{10 \times 10^{-4} \text{cm}} = 10^3 \text{ V/cm}$$

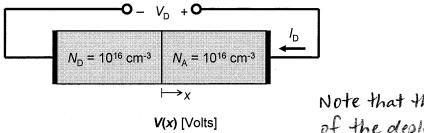
From plot on Page 1, Mn = 1200 cm2/V.s

c) Qualitatively (no calculations required), how would the resistivity of this sample change if it were to be additionally doped uniformly with 2×10¹⁶ cm⁻³ phosphorus? Explain briefly. [4 pts]

Since N_D > N_A, this sample is now n-type, with n=N_D-N_A=10¹⁶cm² From the plot on Page I, un=900cm²/Vis, which is 2X greater than the hole mobility in the uncompensated sample. Since the majority-carrier concentration is unchanged, and the majority-carrier mobility Page 3 is doubled, the resistivity is halved (i.e. p is reduced by a factor of 2.)

Problem 2 [15 points]: PN Junctions

Consider a Si PN junction diode, maintained at T = 300K, with a structure and potential distribution as shown.



$$V(x)$$
 [Volts] $\rightarrow x$ [μ m]

Note that the width of the depletion region is 0.4 Mm = 0.4 × 10-4cm.

a) Calculate the built-in potential, V_0 . [4 pts]

$$V_0 = V_T \ln \left(\frac{N_A N_D}{n_i^2} \right) = 0.026 \ln \left(\frac{10^{16} \cdot 10^{16}}{10^{20}} \right) = 0.026 \ln \left(10^{12} \right)$$

$$= 12 \cdot 0.026 \ln (10) = 12 \cdot 0.06 = 0.72 \text{ V}$$

b) What is the applied voltage, V_D ? Is this diode forward or reverse biased? (Circle one.) [7 pts]

$$Wdep = \sqrt{\frac{2 \cdot \epsilon_{si}}{q} \left(\frac{1}{N_A} + \frac{1}{N_D}\right) (V_0 - V_0)} = \sqrt{\frac{4 \cdot \epsilon_{si}}{2 \cdot N} (V_0 - V_0)}$$
 where $N = 10^{16} \text{ cm}^{-2}$

$$= V_0 - V_D = \frac{q W_{dep}^2 N}{4 \epsilon_{si}} = \frac{(1.6 \times 10^{-14})(0.4 \times 10^{-4})^2 (10^{16})}{4 \times 10^{-12}} = 0.64 V$$

$$V_D = V_0 - 0.64V = 0.72V - 0.64V = 0.08V$$

c) Calculate the areal junction (depletion) capacitance. [4 pts]

$$C_{dep} = \frac{E_{Si}}{W_{dep}} = \frac{10^{-12} \text{ F/cm}}{0.4 \times 10^{-4} \text{ cm}} = \frac{2.5 \times 10^8 \text{ F/cm}^2}{2.5 \times 10^8 \text{ F/cm}^2}$$

Problem 3 [15 points]: Bipolar Junction Transistor Design

a) Why is the base region doped less heavily than the emitter region? [3 pts]

The ratio of carrier diffusion into the base (which determines I_c) to carrier diffusion into the emitter (which determines I_B) is proportional to NE/NB. Thus, to achieve large current gain $\beta = I_c/I_B$,

NE should be much larger than NB.

b) Why is the base region doped more heavily than the collector region? [3 pts]

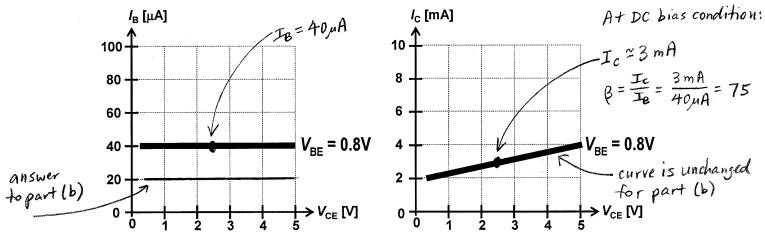
VA and hence the BJT output resistance Fo), the width of the collectorjunction depletion region in the base should be minimized, by making Ne much greater than No so that most of the depletion region resides within the

c) Indicate in the table below (by checking the appropriate box) how the BJT parameters would change, if the base width were to be increased (e.g. by 2×). Provide qualitative reasoning for your answers. [9 pts]

BJT Parameter will **Brief Justification** not change Parameter (No equations or formulas!) increase decrease significantly The minority-carrier concentration gradient would decrease, so that the minority-carrier diffusion Reverse saturation current through the base (into current, $I_{\rm S}$ the collector) would decrease. So long as the quasi-neutral base width is much shorter than the Common-emitter minority-carrier diffusion length, DC current gain, It is primarily supplying carrier diffusion into the emitter, which does not depend on WB. Ic, due to carrier diffusion in the base, would decrease. The percentage change in quasi-neutral base width (WB), for a given change in base-collector reverse bias, would Early voltage, V_A be smaller, so base-width modulation would be decreased.

$\underline{Problem~4}$ [15 points]: Bipolar Junction Transistor $\emph{I-V}$ and Small-Signal Model

Consider a BJT with the *I-V* characteristics as shown below.

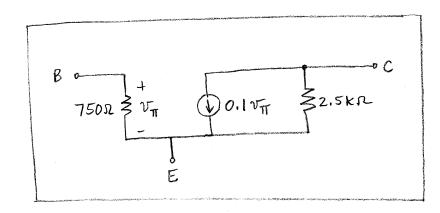


Draw the small-signal model for the BJT for the DC bias condition $V_{\rm BE} = 0.8 \, \rm V$, $V_{\rm CE} = 2.5 \, \rm V$. [12 pts] (Indicate numerical values and units for r_{π} , $g_{\rm m}$, and $r_{\rm o}$, and label the transistor terminals.)

$$g_{m} = \frac{I_{c}}{V_{T}} = \frac{3 \times 10^{-3} A}{0.026 \text{ V}} \approx 0.15$$

$$r_{\pi} = \frac{\beta}{3m} \approx \frac{75}{0.1} = 750 \Omega$$

ro = the inverse slope of the Ie vs. VcE characteristic = 5V / 2mA = 2.5 ks.



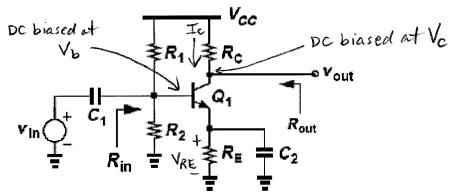
b) Show qualitatively (by sketching curves on each of the plots above) how the *I-V* characteristics would change if the emitter dopant concentration were to be increased by a factor of 2. [3 pts]

If NE increases by 2X, IB & NE would decrease by 2X.

Ic is not strongly dependent on NE, so the Ic vs. Vce characteristic would not be affected significantly,

Problem 5 [20 points]: BJT Amplifier

Consider the BJT amplifier stage shown below, operating at T = 300K with a bias current $I_C = 0.1$ mA. Assume $I_S = 1 \times 10^{-16}$ A, $\beta = 100$, $V_A = \infty$. $R_C = 10$ k Ω , $R_E = 5$ k Ω , and $V_{CC} = 2.5$ V. Note that $e^{0.72/0.026} \cong 10^{12}$.



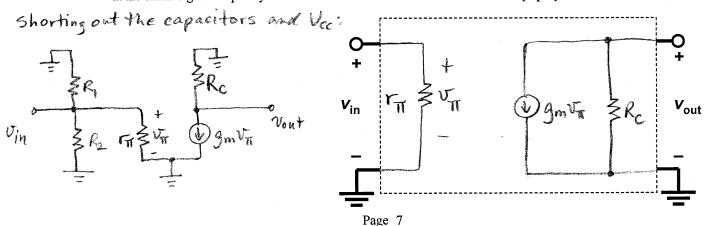
- a) What is the purpose of R_1 and R_2 ? [2 pts] to establish the DC bias voltage for the base of the BJT.
- b) What is the purpose of RE? [2 pts]

 to reduce the error in Ic (hence 3m, rT) resulting from

 errors in the values of R, and R2.

 $V_c = V_{cc} - I_c R_c = 2.5 - (0.1 \text{ mA})(10 \text{ kJL}) = 2.5 \text{ V} - 1 \text{ V} = 1.5 \text{ V}$ Since $V_c > V_b$, collector junction is reverse-biased. $V_c > V_b$ d) Draw (in the box provided) the most simplified circuit that can be used for AC analysis to determine the

d) Draw (in the box provided) the most simplified circuit that can be used for AC analysis to determine the small-signal voltage gain, A_v . You can assume that C_1 and C_2 are large, so that their impedances are negligible at the small-signal frequency of interest. Label the various circuit elements. [6 pts]



Problem 5 (continued)

e) Write expressions for the small-signal voltage gain (A_v) , input resistance (R_{in}) , output resistance (R_{out}) . [5 pts]

Circuit for analysis of Rin =
$$\frac{v_x}{i_x}$$
:

$$R_{in} = R_1 || R_2 || r_{\pi}$$

$$V_{in}=0 R_{i}||R_{2}|| R_{3}||R_{4}|| R_{5}||R_{5}|| R_{6}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_{5}||R_$$